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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Number : 10/728,775 Confirmation No. 2372
Applicant : Sung-Kwon LEE et al.
Filed : December 8, 2003
Tech Cntr/AU : 2813
Examiner : Thanh T Nguyen
Entitled : METHOD FOR FABRICATING SEMICONDUCTOR DEVICE
WITH FINE PATTERNS

Attorney Reference : 123037-05005024
Customer Number : 43569

MAIL STOP ISSUE FEE

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Sir:

Pursuant to 37 CFR §1.97 and 1.56, the attention of the U.S. Patent and Trademark Office is hereby directed to the following disclosures made herein, which include:

REFERENCES AND RELEVANCY

- ☐ Applicant(s) wish(es) to make of record the documents listed on the attached Form PTO-1449. Copies of the listed documents are attached, where required, as are any readily available full or partial English translations of any non-English language documents.
- ☐ Applicant(s) wish(es) to make of record the documents listed on the attached Form PTO-1449. The references cited herein were cited for consideration in the parent application, and, pursuant to 37 CFR 1.98(d), copies of the cited references can be found in the file of the parent application (U.S. Serial No. , filed).
- ☐ Applicant(s) wish(es) to make of record the documents listed on the attached Form PTO-1449. The references cited herein were cited in the International Search Report issued for the corresponding International application, and copies of the International Search Report and the cited references are attached for the Examiner's consideration.
- ☒ Applicant(s) wish(es) to make of record the documents listed on the attached Form PTO-1449. The references cited herein were cited in a communication from a foreign or international patent office in a counterpart foreign or international application(s), and copies of both the relevant communication and the cited references, where required, are attached for the Examiner's consideration.

11/04/2005 SZWDIEI-00000090 503121 10728775

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CERTIFICATION

The undersigned certifies that, pursuant to 37 CFR §1.97(e)(1),

- ☒ each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign or international patent office in a counterpart foreign or international application not more than three months prior to the filing of this Statement.

RELATED CASES

- ☐ Identified in the attached Appendix are related applications directed to related technical subject matter. Copies of the related applications, where required, are attached for the Examiner's consideration. *The identification of the related U.S. patent applications is not to be construed as a waiver of secrecy for those applications, now or upon issuance of the present application as a patent.*

BASIS FOR CONSIDERATION

This Information Disclosure Statement is filed:

- ☐ within three months of the filing date of the application and/or before the mailing date of a first Official Action on the merits, and no fee is required [37 C.F.R. §1.97(b)].
- ☐ with the appropriate certification, and no fee is required [37 C.F.R. §1.97(e)(1)].
- ☐ after the mailing date of the first Official Action on the merits, but prior to the issuance of a Final Official Action or a Notice of Allowance, and the requisite fee, if necessary, is authorized herein for payment [37 C.F.R. §1.97(c)].
- ☒ after the mailing date of the Final Official Action or Notice of Allowance, but prior to the payment of the issue fee, the requisite certification under 37 CFR §1.97(e)(1) is made herein, and the requisite fee, if necessary, is authorized herein for payment [37 C.F.R. §1.97(d)].
- ☐ with a Request for Continued Examination (RCE), and no fee is required [37 C.F.R. §1.97(b)(4)].

FEE AUTHORIZATION

- ☒ Authorization is hereby given to charge any deficient fee(s) under 37 CFR §1.16 and §1.17 as necessary to ensure the consideration of this disclosure, or to credit any fee overpayments, to Deposit Account No. 503-121.
- ☒ Authorization is hereby given to charge the requisite fee of \$180 (Fee Code 1806) for submission of this Information Disclosure Statement to Deposit Account No. 503-121.

It is respectfully requested that this information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

The Examiner is further respectfully requested to return of a copy of the enclosed Form PTO-1449 with the Examiner's initials in the left column.

The examination and allowance of this Application is respectfully requested.

Respectfully Submitted,

MAYER BROWN ROWE & MAW LLP

By: 

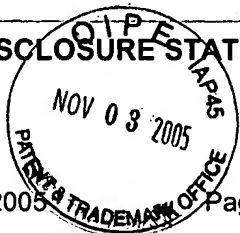
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Date: November 3, 2005

Attachment(s): PTO Form 1449
Cited References

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



Date: November 3, 2005 Page 1 of 1

Attorney Reference: 123037-05005024

Applicant: Sung-Kwon LEE et al.

Application Serial No. 10/728,775

Filing Date: December 8, 2003

Examiner: Thanh T
Nguyen

Group Art Unit: 2813

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR	6,200,907	03/2001	Wang et al.			
BR	6,283,131	09/2001	Chen et al.			
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Translation Readily Available		English Abstract	
				Enclosed	No	Enclosed	No
OR	1020000025529	05/2000	KR			X	
PR							
QR							
RR							
SR							
TR							
UR							
VR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

WR	
XR	
YR	
ZR	
AAR	
BBR	

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.